



# BATTERY QUALITY CONTROL VIA HIGH-THROUGHPUT CT SCANNING

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2024 NASA Aerospace Battery Workshop

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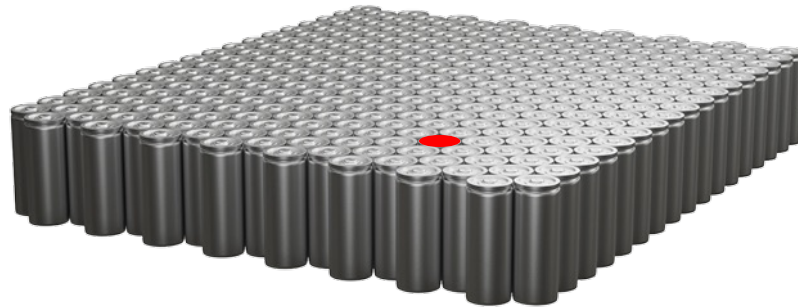
# THREE PROBLEMS FACING THE INDUSTRY



## SAFETY



## RELIABILITY



## MANUFACTURABILITY



All three problems are closely related to **battery quality**

Attia et al. (2024). [arXiv 10.48550/arXiv.2403.01065](https://arxiv.org/abs/10.48550/arXiv.2403.01065)

# CELL-LEVEL DEFECTS



## a. Open-circuit defects



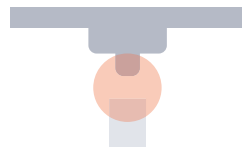
Tab weld failure



Tab tear



Terminal corrosion



Premature activation of protection device

## b. Short-circuit defects

### Direct short



Metallic particle contaminants



Metallic burrs and tears from tabs and foil



Missing/insufficient separator overhang



Hole/local weak spot in separator

### Plating-induced short



Insufficient electrode overhang



Missing/insufficient electrode coating



Overloaded electrode coating



Electrode wrinkle



Electrode buckle

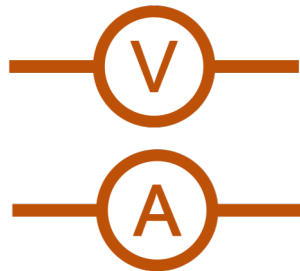
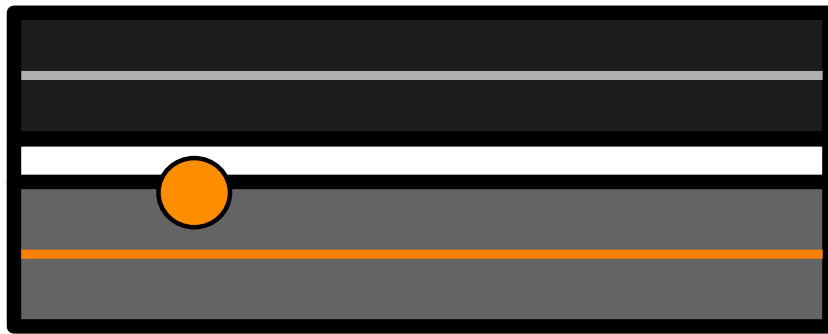


Sharp electrode curvature

Subtle structural defects can cause reliability and safety issues

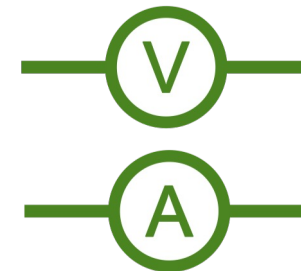
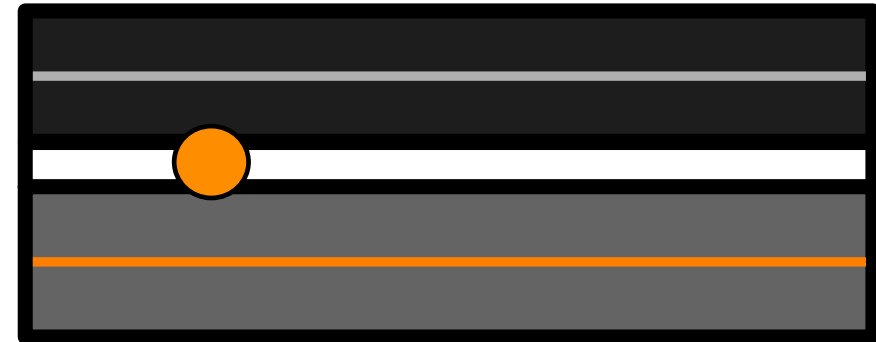
Attia et al. (2024). [arXiv 10.48550/arXiv.2403.01065](https://arxiv.org/abs/10.48550/arXiv.2403.01065)

Metallic particle present, but not yet connecting anode and cathode



✗ No electrochemical signal

Metallic particle present and connecting anode and cathode



✓ Electrochemical signal

Latent defects have no electrochemical signal until failure



# INSPECTION TECHNIQUES



	Non-destructive	Scalable to ≤10s/cell	Full cell inspection	Spatially resolved	Resolution of ≤50 μm
Cycling & Storage	✗	✗	✓	✗	✗
Ultra High Precision Coulometry (UHPC)	✗	✗	✓	✗	✗
Electrochemical Impedance Spectroscopy (EIS)	✓	✗	✓	✗	✗
OCV decay during formation	✓	✗	✓	✗	✗
High Potential testing (HiPot)	✓	✓	✓	✗	✗
Dissection	✗	✗	✓	✓	✓
Cross section	✗	✗	✗	✓	✓
In-line vision	✓	✓	✗	✓	✓
Acoustics	✓	✓	✓	✓	✗
2D X-ray imaging	✓	✓	✗	✓	✓
3D X-ray imaging (CT scanning)	✓		✓	✓	✓

# GLIMPSE: IMPROVING SCAN TIME



Optimized hardware  
(X-ray source, detector, fixturing...)



Optimized scan recipe  
(source, detector, positions...)



Image enhancement  
(corrections, denoising, ...)



Nikon scanner

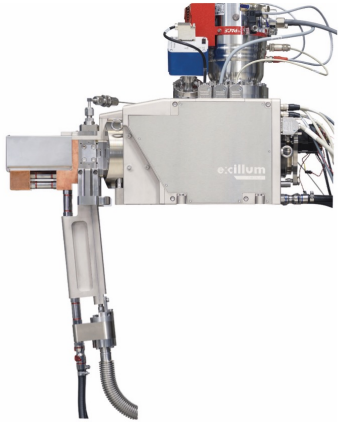
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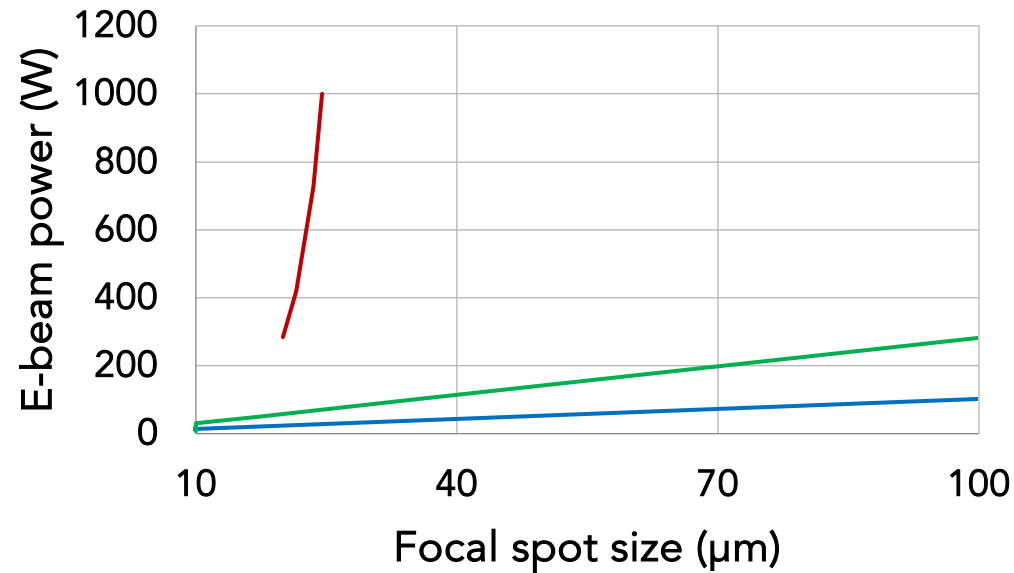
Glimpse's standard cylindrical cell scans take 2 minutes



## FASTER SCANS VIA THE "SUPERSCANNER"



Excillum MetalJet X-ray source



- Non-rotating solid source
  - Rotating solid source
  - Liquid metal source\*
- 3x power<sup>†</sup>  
6x power<sup>†</sup>

\*at 160 keV

†at iso-spot size



VisiConsult + Glimpse "superscanner"

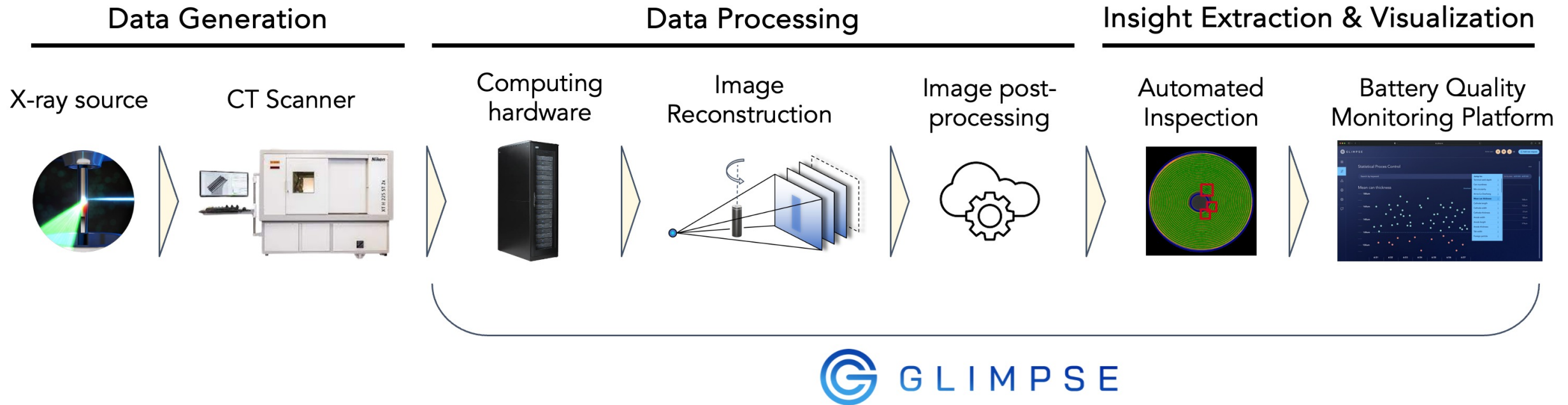
≤10 seconds/scan with next-generation CT scanner (VCB2)

# GLIMPSE: IMPROVING ANALYSIS TIME



Each scan of a 2170 battery is ~50 GB 🤯

10 sec/scan = 18 TB/hour. How do we extract insights from it?



The old way: Slow, local, expensive 🐢 ⌚

With Glimpse: Fast, automatic, collaborative 🐇 ⌚

Fast scan time + fast analysis time = fast “time to insights”

# THE GLIMPSE PORTAL™: SINGLE SCAN VIEWER



Condon et al. (2024). *Data in Brief* 10.1016/j.dib.2024.110614

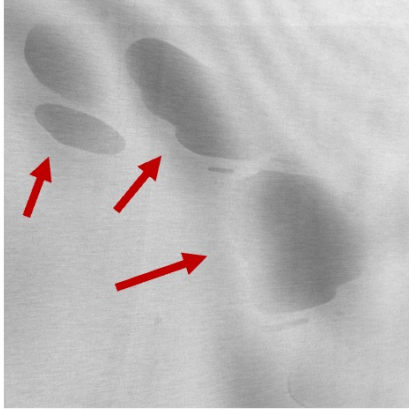
# THE GLIMPSE PORTAL™: AUTOMATED INSPECTION DASHBOARDS



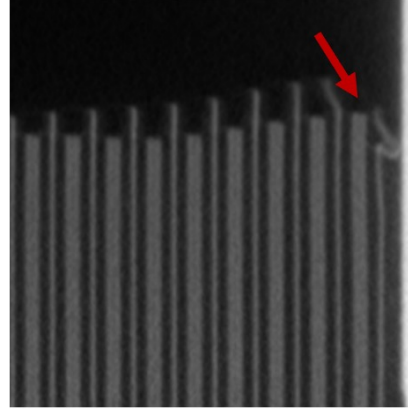
Condon et al. (2024). *Data in Brief* 10.1016/j.dib.2024.110614



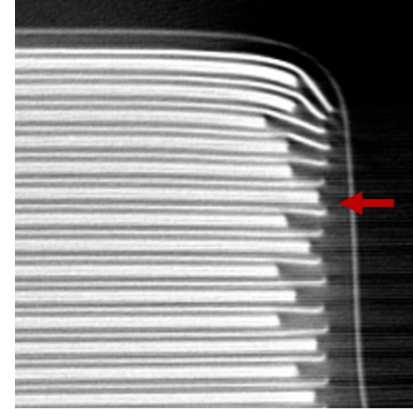
## SOME CT-DETECTABLE DEFECTS



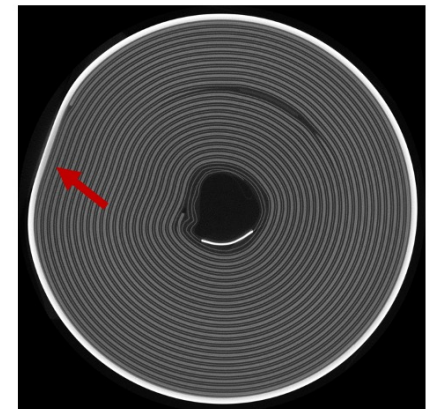
*Gas bubbles*



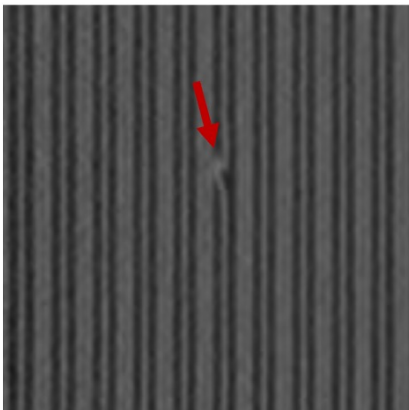
*Folded anode tip*



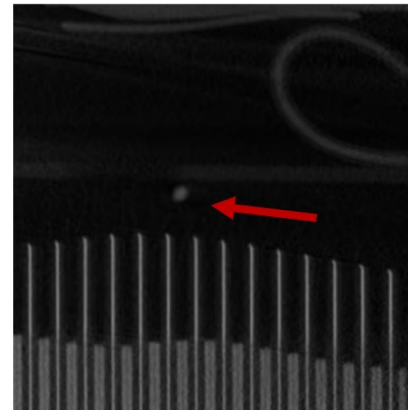
*Electrode overhang violation*



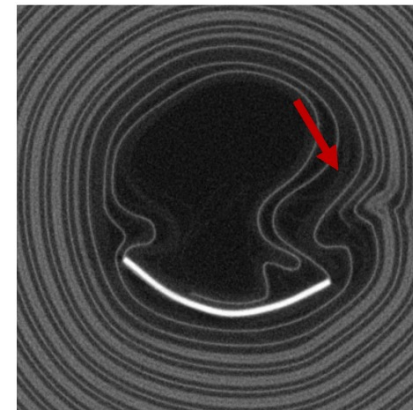
*Dented can*



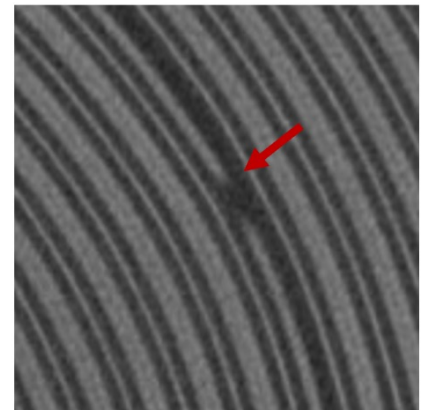
*Wrinkled electrode*



*Metallic contaminant*



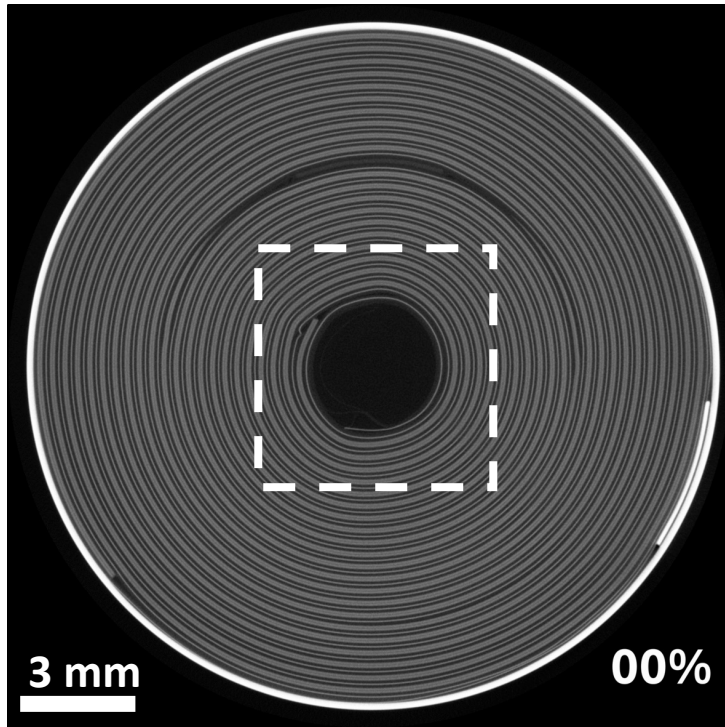
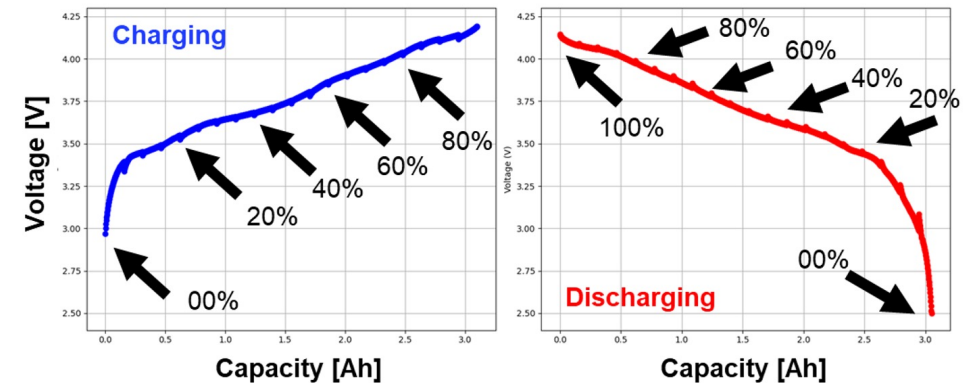
*Buckled jellyroll*



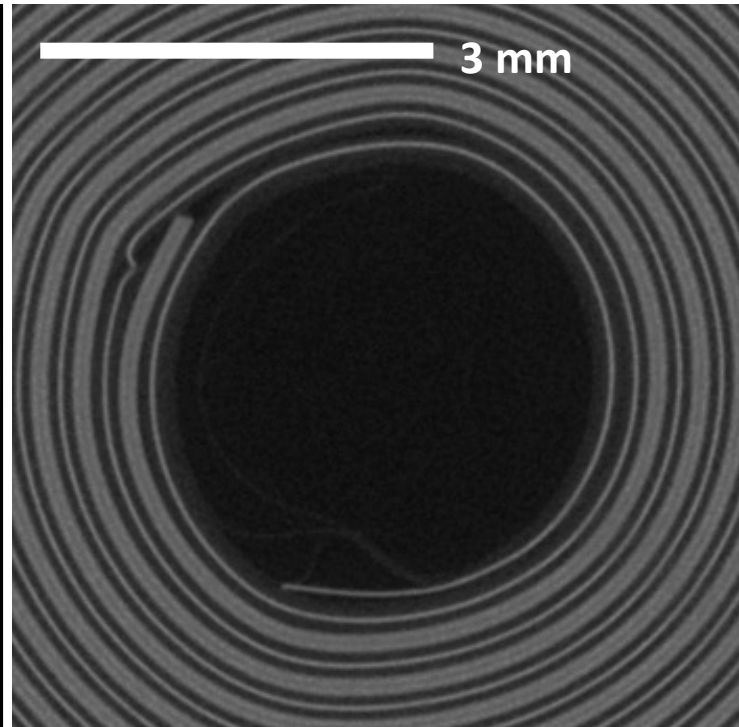
*Missing electrode coating*

# STUDYING BATTERY SWELLING AND AGING VIA CT

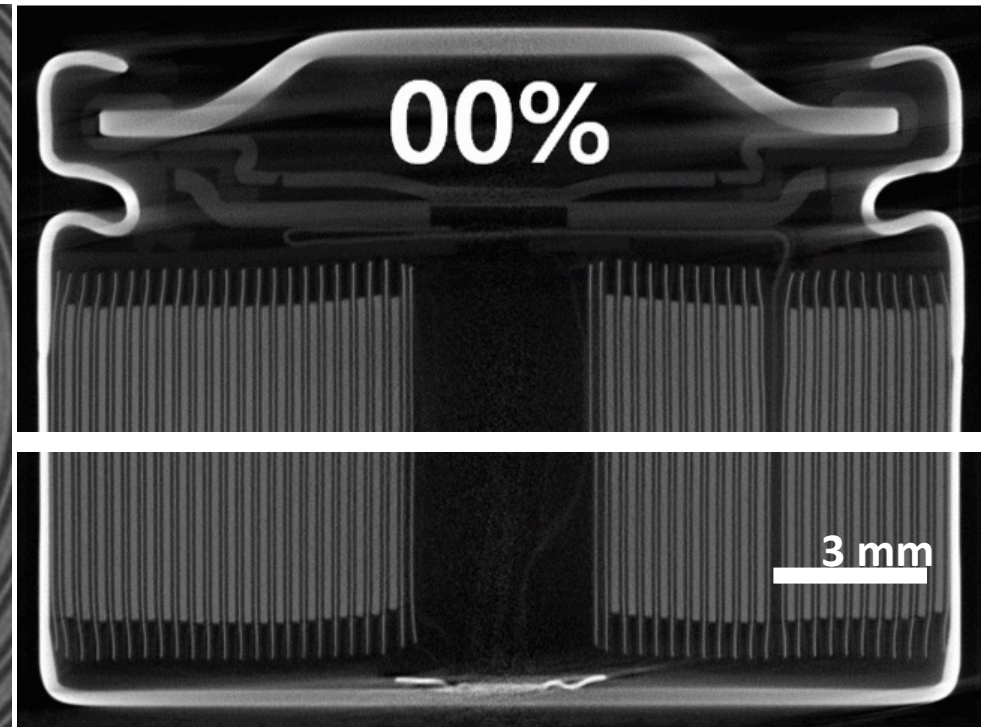
EVE 18650 LIB cell



Radial slice



Magnified



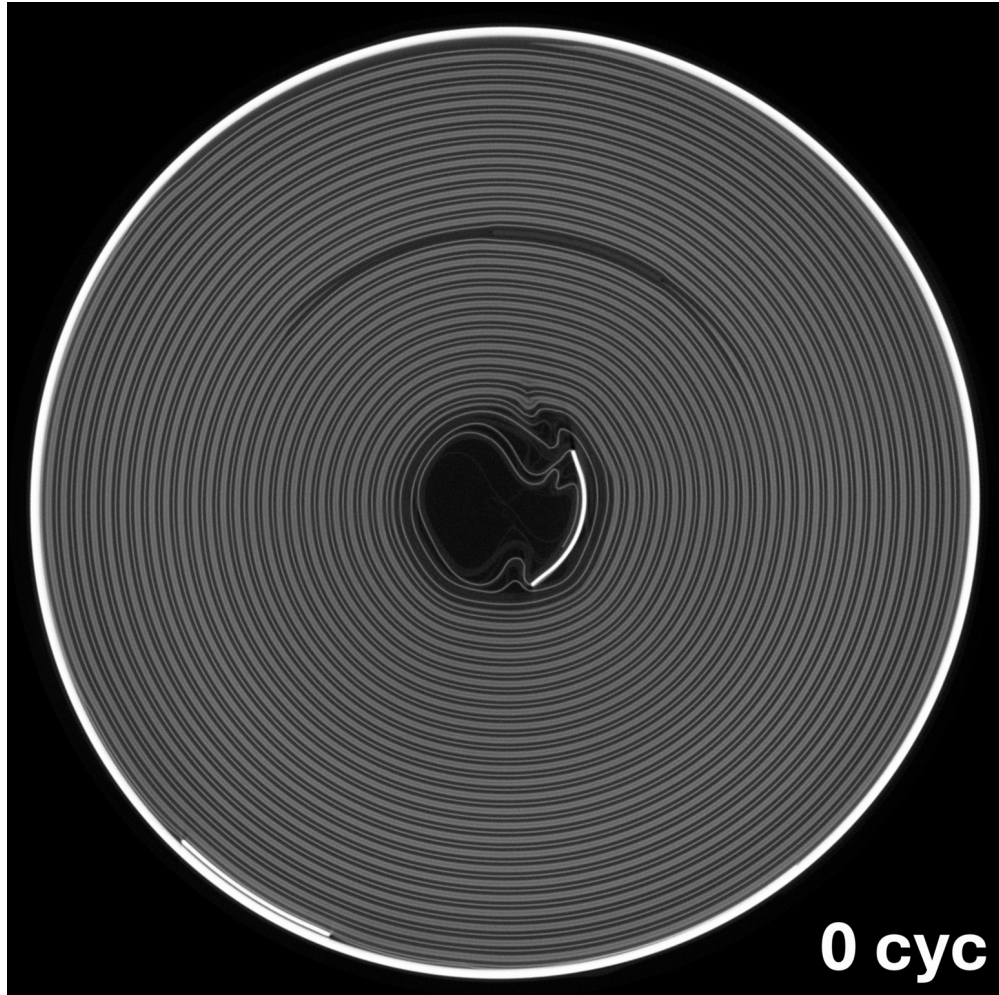
Axial slice



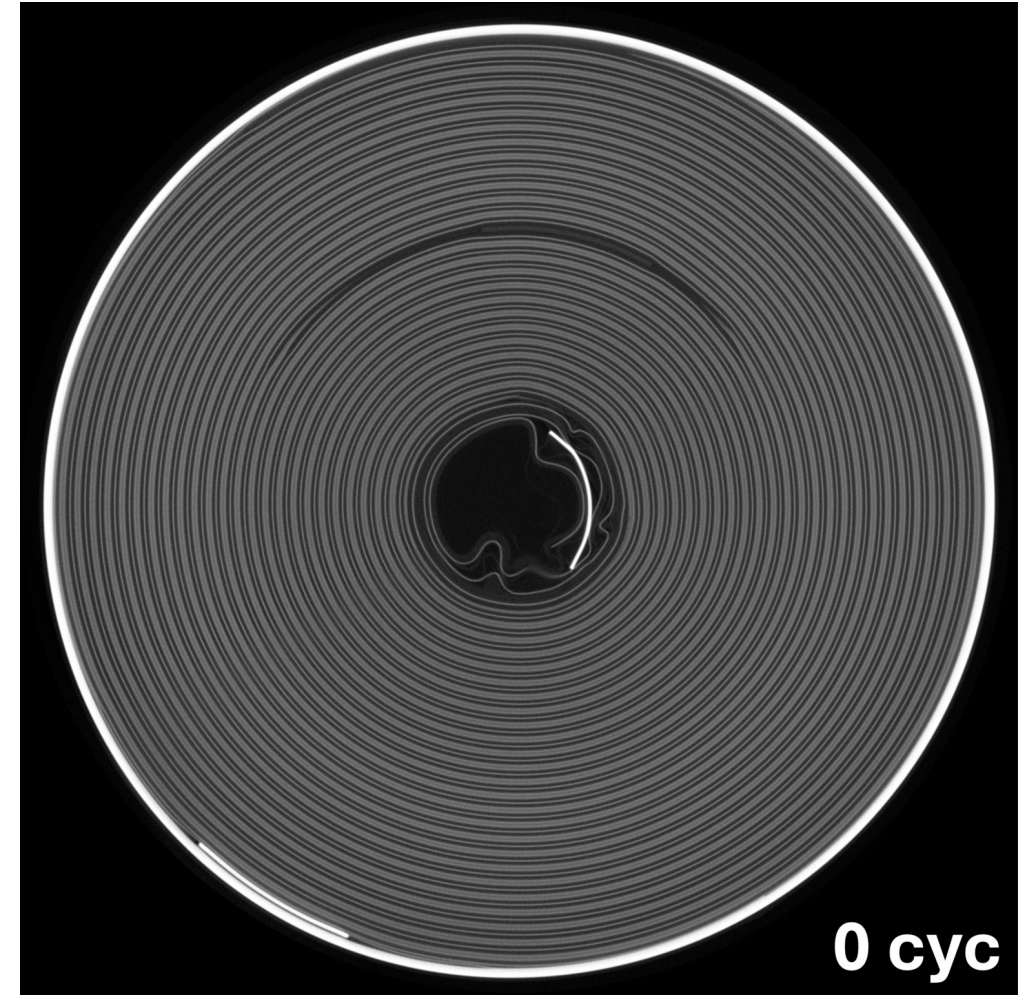
## STUDYING BATTERY SWELLING AND AGING VIA CT



Buckling present at cycle 0

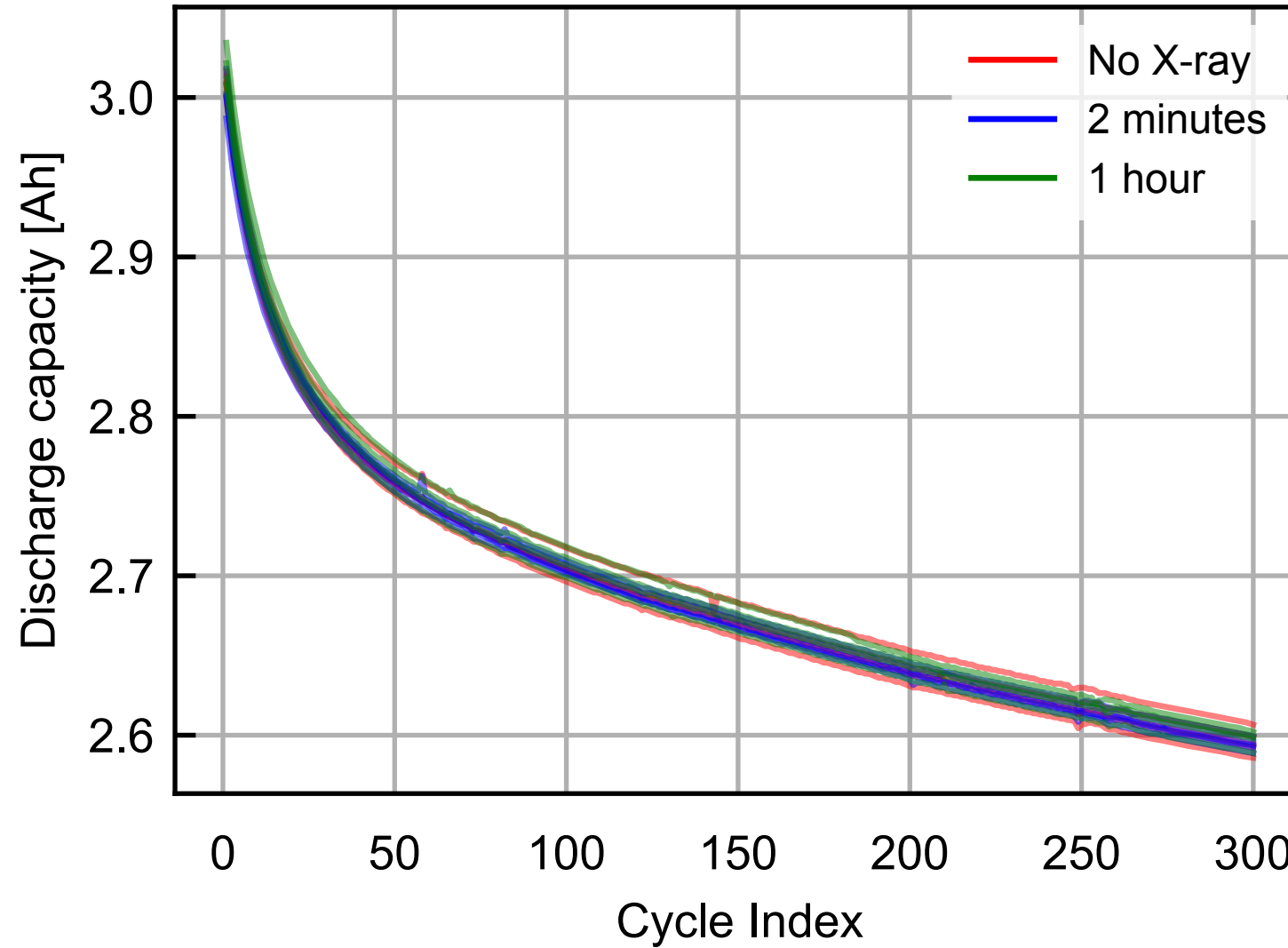


Buckling **not** present at cycle 0



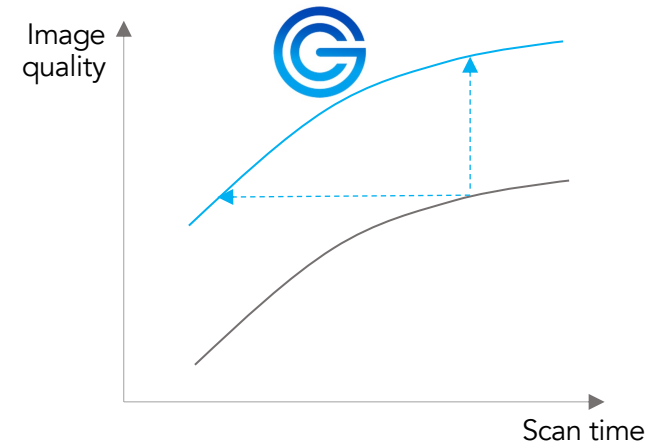
Vapcell F56 LIB cell

## VALIDATION: X-RAY BEAM DAMAGE

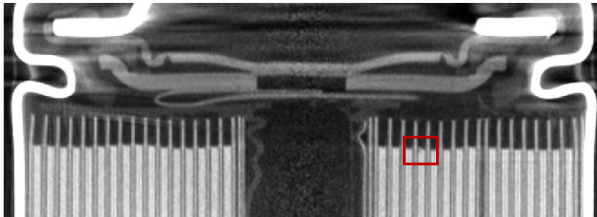


Min, Condon, Attia (2024). *ECSarXiv* 10.17605/OSF.IO/R9VEM

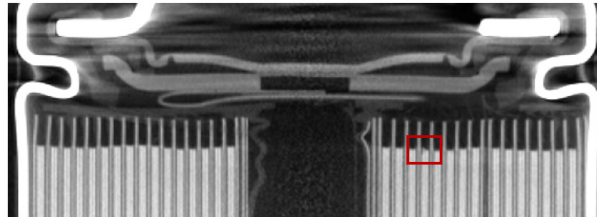
# VALIDATION: SCAN TIME VS. IMAGE QUALITY



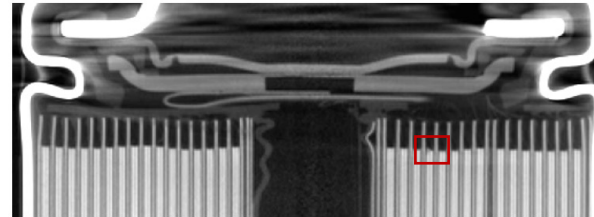
1 min



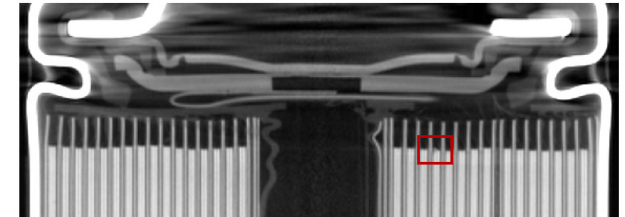
2 min



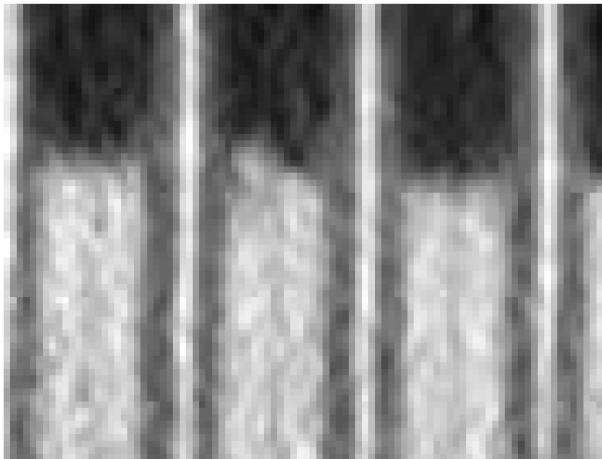
8 min



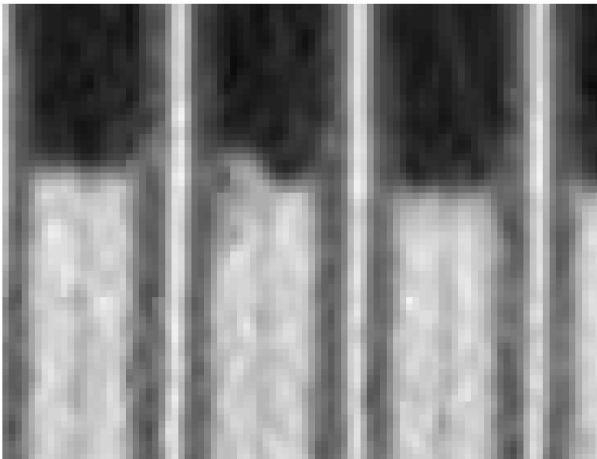
16 min



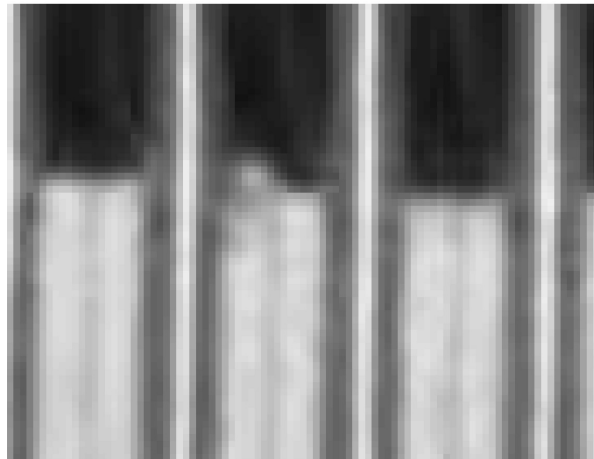
1 min



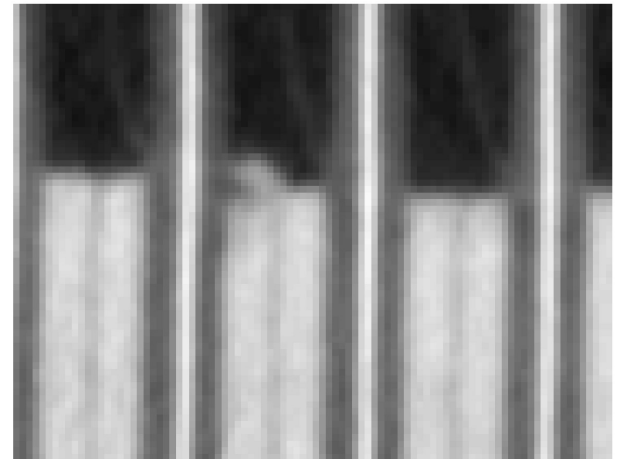
2 min



8 min

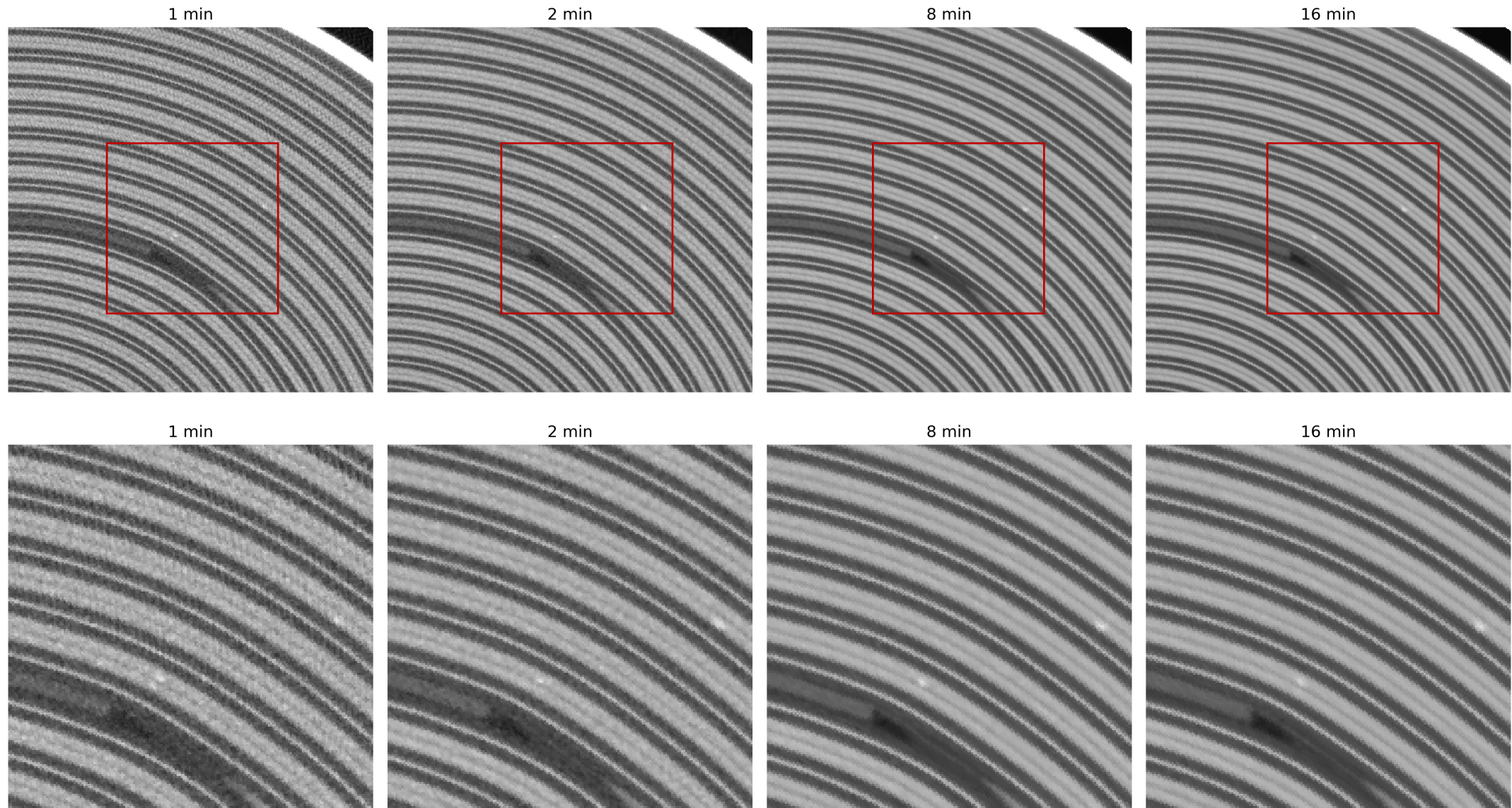


16 min

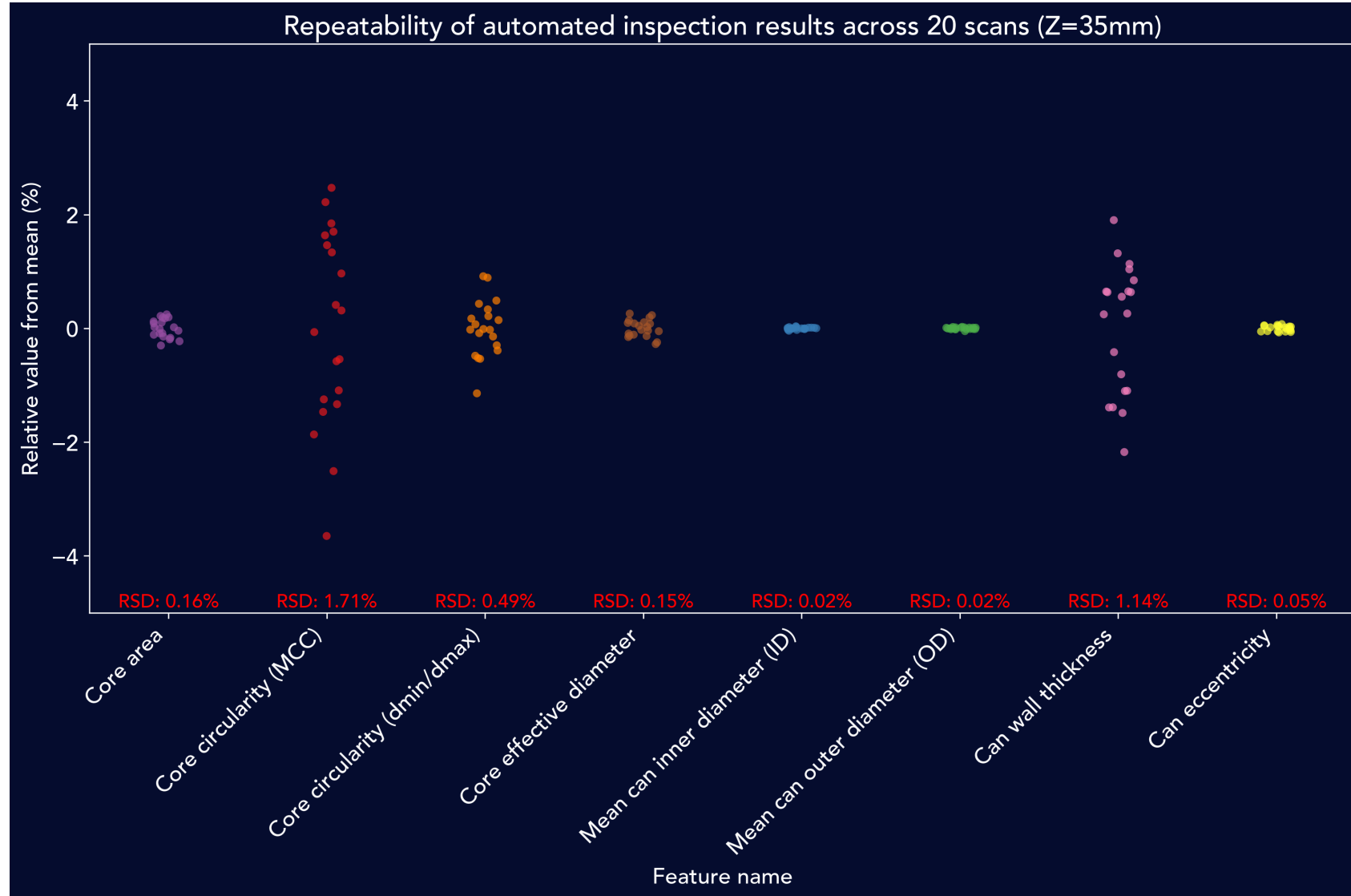




## VALIDATION: SCAN TIME VS. IMAGE QUALITY



# VALIDATION: ALGORITHM REPEATABILITY

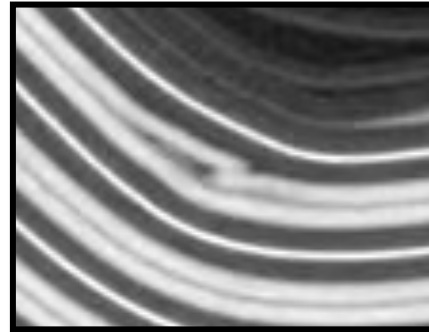


## GLIMPSE'S WORK WITH NASA: SAMSUNG ICR18650-26F EVA SCAN REVIEW

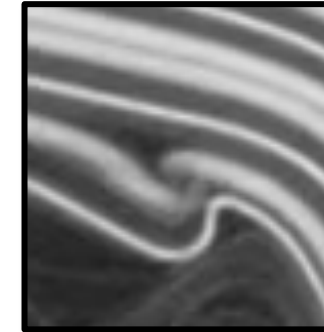
Credit:  
Douglas Zupan  
Sean Murray  
Martin Martinez  
Sam Russell



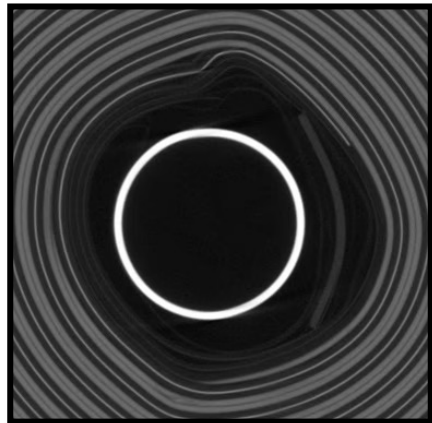
*Pits in cell cap crimp area*



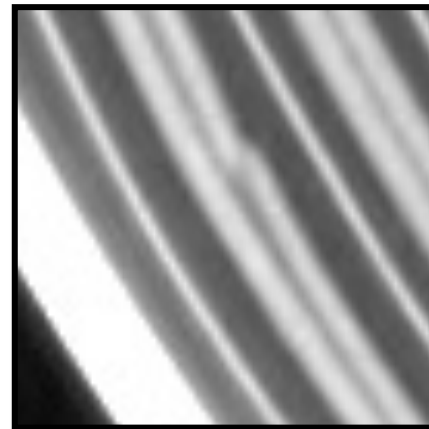
*Delamination/cracking  
of active material*



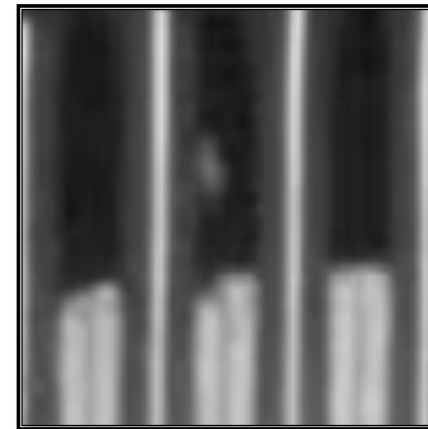
*Delamination/cracking  
of active material*



*Poor core circularity*



*Delamination/cracking  
of active material*



*Liberated active  
material*

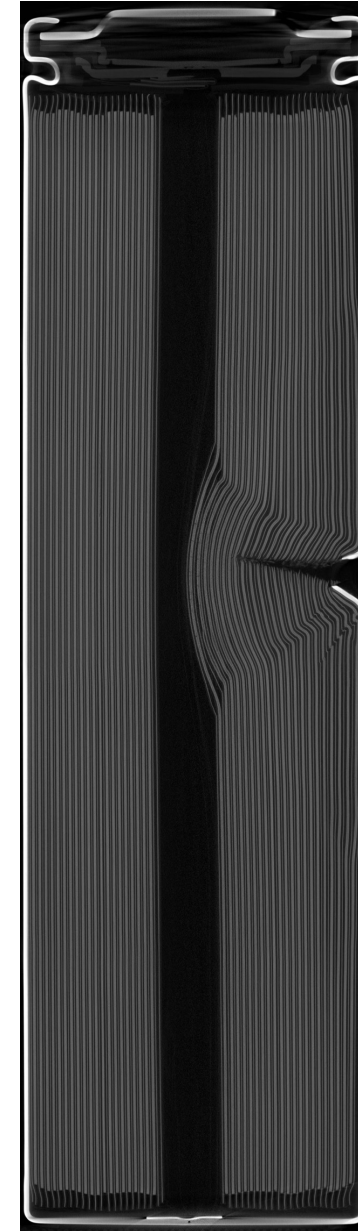
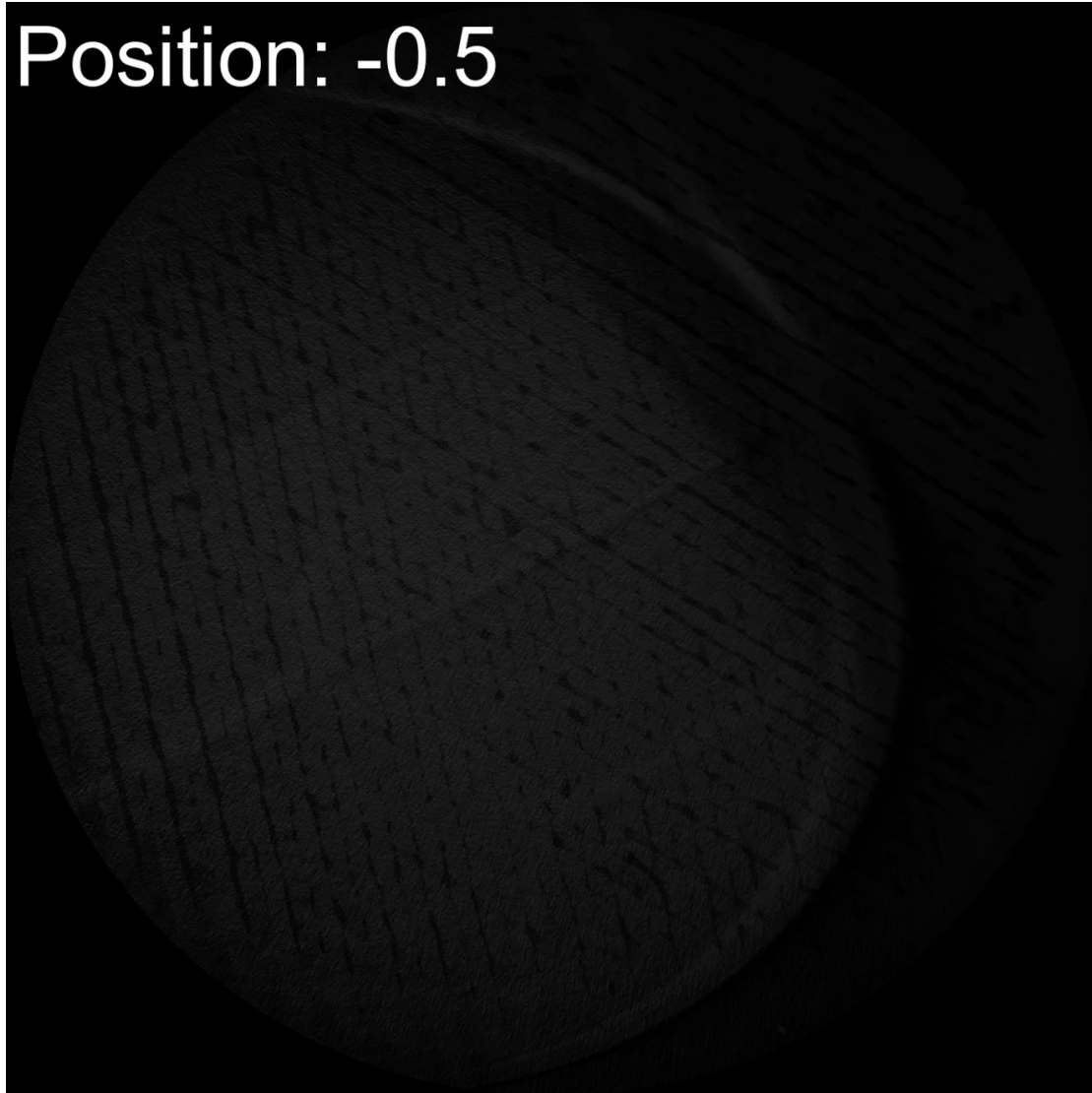


*Gap in active  
material*



## GLIMPSE'S WORK WITH NASA: NAIL PENETRATION CELL

Position: -0.5



Credit:  
Eric Darcy  
David Petrushenko  
Jesus Trillo



## GLIMPSE'S WORK WITH NASA: INVESTIGATING NEW CELL DESIGNS

Credit:  
Eric Darcy  
David Petrushenko  
Jesus Trillo



LG M52V



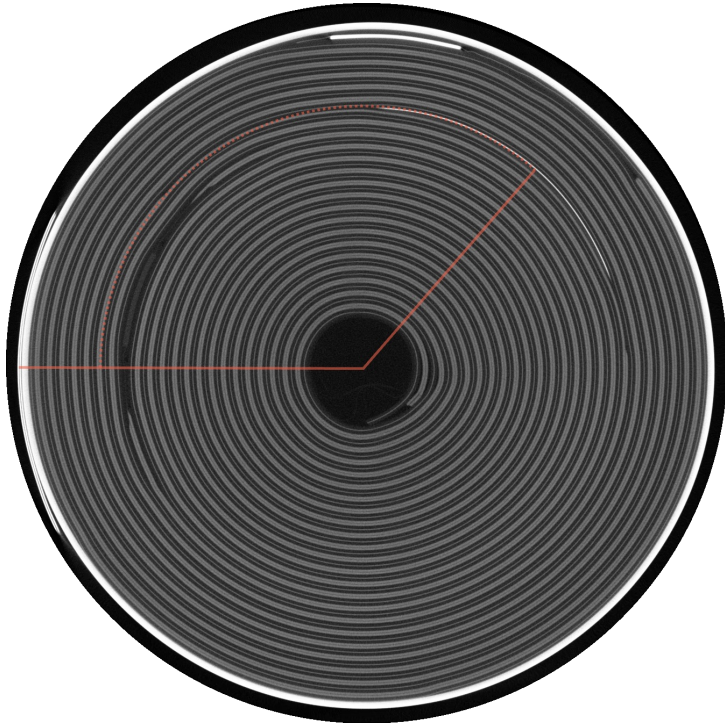
Samsung 53G1



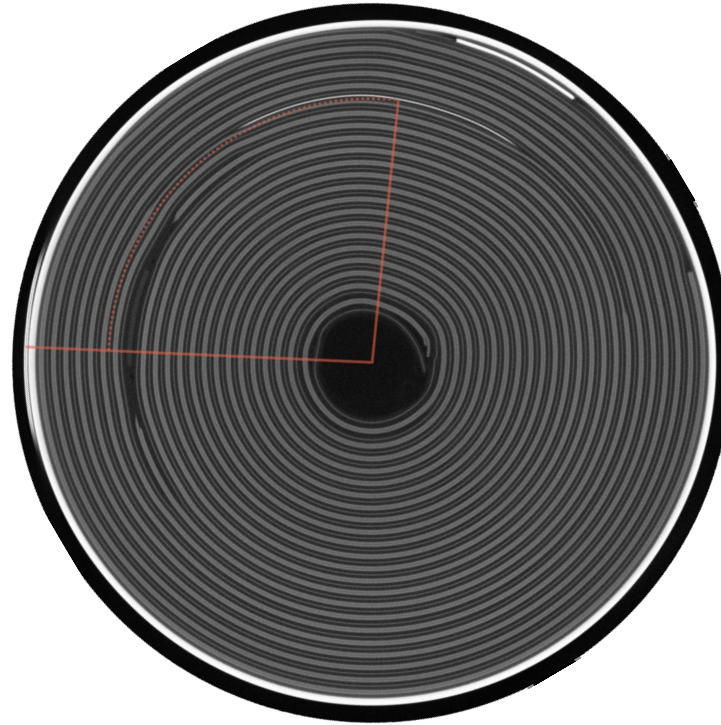


## GLIMPSE'S WORK WITH NASA: INTERNAL SHORT CIRCUIT DEVICE (ISCD) CELLS

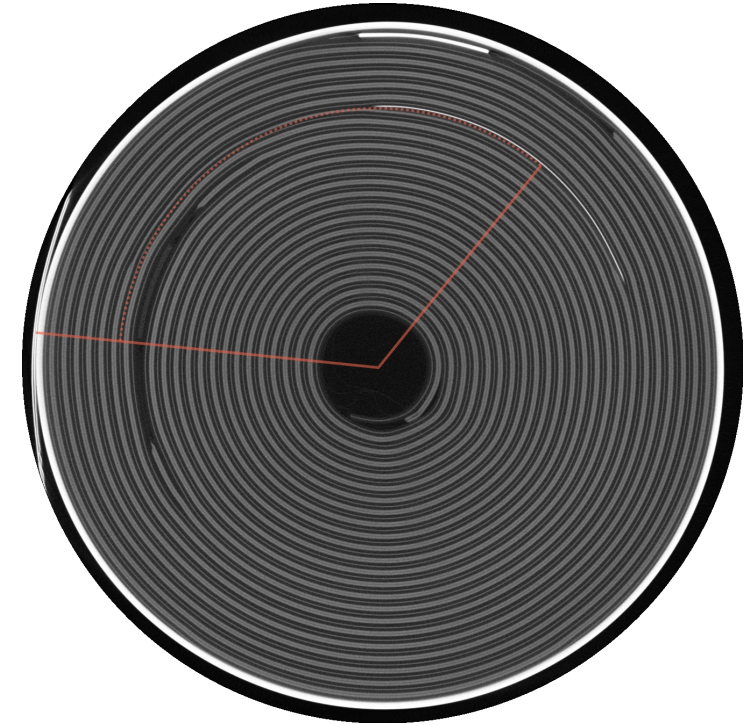
Credit:  
Eric Darcy  
David Petrushenko  
Jesus Trillo  
Donal Finegan



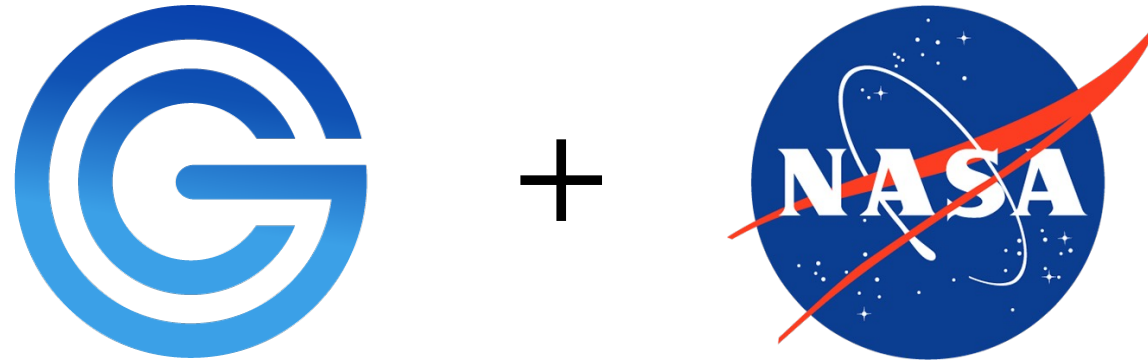
Angle: 130°



Angle: 93°



Angle: 122°



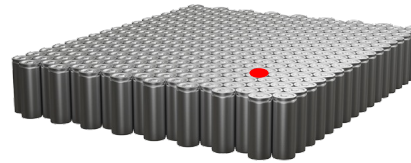
**Goal:** Drive down cost & effort for aerospace organizations to evaluate battery quality via CT

1. **Glimpse:** Reduce scan time/cost ("superscanner" + new algorithms)
2. **Glimpse + NASA:** Understand impact of defects for NASA mission profiles (cycling studies)
3. **Glimpse + NASA:** Map out confidence in defect detection vs. scan time/cost
4. **Glimpse + NASA:** Develop automated defect detection algorithms for relevant defects

# CONCLUSIONS



1. Battery quality is a big problem



2. Glimpse's mission is to enable **battery quality at scale**  
by driving down the scan time & analysis time of battery CT scanning
3. Glimpse's technology is unlocking new insights into NASA's cell quality
4. Glimpse and NASA can continue to work together to reduce cost and improve effectiveness of defect screening





GLIMPSE

ENABLING BATTERY QUALITY AT SCALE